Form PTO 1449 (Modified)		U.S. DEPARTMENT OF PATENT AND TRADES	F COMMERCE MARK OFFICE	ATTY DOCKET NO. 238397US-2 DIV		APPLN. SI	ERIAL NO. LAP <del>PLIGA</del>	TION
•	REFERENCES CITED BY APPLICANT  NATSUKO NOBUKUNI, ET AL.			25 17 19				
LIST OF F	REFER	LENCES CITED BY APPL	LICANT					
	FILED HEREWITH GROUP			2653				
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL,		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB	FILING IF APPRO	
Pla	AA	5,732,062	03/24/98	Yokoi, et al.	<del></del>			<del></del>
Pla	ΔB	5,848,043	12/08/98	Takada, et al.	]			<del></del>
W	AC	5,530,688	06/1996	Hurst, Jr., et al.				
N	AD	6.294,310	09/2001	Ohno, et al.				
No	AE	5,703,855	12/1997	Kirino et al.	]	<del>                                     </del>		
0/1	AF	5,568,461	10/1996	Nishiuchi, et al.				
The same of the sa	AG	6,256,277 B1	07/03/01	Saga et al.	1			
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FOREIGN PATENT DOCUMENTS								
اا		DOCUMENT NUMBER	DATE	COUNTRY	COUNTRY		TRANSLATIONS	NO
ol	AO	62-259229	11/11/87	Japan				X
2/	ΑP	63-266632	11/02/88	Japan				X
1	AQ	63-22439	01/29/88	3 Japan				x
N	AR	7-37252	02/07/95	5 Japan		]		×
ng	AS	9-7176	01/10/97	7 Japan				x
ag	AT	8-287465	11/01/96	6 Japan		T		х
12	AU	9-282661	10/31/97	7 Japan		1—		x
de	av	7-37251	02/07/95	5 Japan	<u></u>	+		X
1	<u> </u>	OTHER RE	FERENCES	(Including Author, Title, Date, Pertine	ent Pages,	etc.)		
<del>                                     </del>	1	N. Nobukuni, et al. J. A	Appl Physics,	"Microstructural changes in GeSbTe film			erwriting in ph	ase-change
ac	AW	optical recording,* Dece	ember 15, 19	95, pages 6980-6988.				
	AX				_			
	AY							
	AZ							
<b> </b>	Щ	Muhammad E		19-	1		1.5/	- / .
Examiner		Primary Eyen	minor	The AUDED		onsidered	10/17	2/04
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Form PTO 1449 (Modified)	· · · · · ·	U.S. DEPARTMENT OF PATENT AND TRADE	COMMERCE MARK OFFICE	ATTY DOCKET NO. 238397US-2 DIV		APPLN. SERIAL NO. NEW APPLICATION		<u>-</u>	
			OBUKUNI, ET AL.						
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				J.S. PATENT DOCU	MENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NA	ME	CLASS	SUB CLASS	FILING DATE IF APPROPRIAT	ΓE
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		·	FO	REIGN PATENT DO	CUMENTS				
		DOCUMENT NUMBER	DATE	COUNTRY TRANSLATES		TRANSLATION S NO			
No	AO	0 867 868	09/30/98	Europe (English)			ļ		
Ng	AP	0 902 424	03/17/99	Europe (English)			1		
t/	AQ	0 388 897	09/26/90	Europe (English)			$\perp$		
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		OTHER REI	FERENCES (	Including Author, 1	itle, Date, Pertine	nt Pages,	etc.)		
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	AZ		<del></del>						
Examiner		Muhamm Primary F			p ?		nsidered	10/17/00	7
*Examiner: In conformance	itlal if r and no	Primary E eference is considered, v ot considered. Include co	vhether or no by of this form	citation is in conformation with next communi	mance with MPEP ( cation to applicant.	609; Draw	line throug	n clauch if notfin	' —

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SHEET 1 OF 1

Form PTO 1449		U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO. 238397US2DIV		SERIAL NO.			
(Modified) PATENT /		PATENT AND TRAD	ENARK OFFICE	238397US2DIV	ARK	10/657,	121		
				APPLICANT					
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Natsuko NOBUKUNI, et al.					
				FILING DATE		GROUP	1		
				September 9, 2003		2655			
				U.S. PATENT DOCUMENTS	S. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE			
A	AA	6,256,286	07/03/2001	M. OGAWA					
	AB								
	AC								
	AD		1		1				
	AE								
	AF								
	AG						<del></del>		
	AH		1		1				
	Al				-		·		
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<b></b>	AL		<del> </del>		<del>                                     </del>				
	AM		†		-	1			
	AN				1				
	·	<u> </u>	FO	REIGN PATENT DOCUMENTS		1			
DOCUMENT DATE COUNTRY TRANSLATION							TRANSLATION		
		NUMBER	DATE	COUNTRY YES					
Res	AO	0 847 049	06/10/1998	EUROPE					
Na	AP	0 217 293	04/08/1987	EUROPE					
VI	AQ.	0 834 874	04/08/1998	EUROPE	PE				
N	AR	1 047 056	10/25/2000	EUROPE					
	AS								
	AT								
	AU			·					
	AV	<u> </u>							
		OTHER R	EFERENCES (	(Including Author, Title, Date, Pertine	nt Pages, e	itc.)			
M. HORIE, et al., Optical Data Storage, Proceedings of SPIE, vol. 4342, XP-002267102, pages 76-87, "MATERIAL CHARACTERIZATION AND APPLICATION OF EUTECTIC SbTe BASED PHASE-CHANGE OPTICAL RECORDING									
d	AW	CHARACTERIZATIO	cal Data Stora N AND APPLIC	ge, Proceedings of SPIE, vol. 4342, XP- CATION OF EUTECTIC SbTe BASED P	002267102 HASE-CHA	, pages 76 NGE OPT	5-87, "MATERIAL TICAL RECORDING		
M	AW	CHARACTERIZATION MEDIA*, April, 2001	N AND APPLIC	ge, Proceedings of SPIE, vol. 4342, XP- CATION OF EUTECTIC SbTe BASED P 1160, September 11, 1998	002267102 HASE-CHA	P. pages 76 NGE OPT	-87, "MATERIAL ICAL RECORDING		
and and		CHARACTERIZATION MEDIA*, April, 2001 Patent Abstracts of Ja	N AND APPLIC	CATION OF EUTECTIC SUTE BASED P	002267102 HASE-CHA	2. pages 76 NNGE OPT	-87, "MATERIAL ICAL RECORDING		
A A		CHARACTERIZATION MEDIA*, April, 2001 Patent Abstracts of Ja Patent Abstracts of Ja	N AND APPLIC pan, JP 10-24 pan, JP 61-02	CATION OF EUTECTIC SbTe BASED P 1160, September 11, 1998 0236, January 29, 1986	HASE-CHA	NGÉ OPT	erences sheet(s) attached		
R R	AX	CHARACTERIZATION MEDIA*, April, 2001 Patent Abstracts of Ja Patent Abstracts of Ja Muha	pan, JP 10-24 pan, JP 61-02	CATION OF EUTECTIC SbTe BASED P 1160, September 11, 1998 0236, January 29, 1986	HASE-CHA	NGË OPT	erences sheet(s) attached		
Examiner	AX AY AZ	CHARACTERIZATION MEDIA*, April, 2001 Patent Abstracts of Ja Patent Abstracts of Ja Muha Prima	pan, JP 10-24 pan, JP 61-02 mmad Ec	CATION OF EUTECTIC SbTe BASED P 1160, September 11, 1998 0236, January 29, 1986	HASE-CHA	litional Ref	erences sheet(s) attached		



## LIST OF RELATED CASES

of g

Docket Number
238397US2 DIV*

Serial or
Patent Number
10/657,121

Filing or Issue Date 09/09/03

Inventor/
Applicant

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10/825,439 .

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NOBUKUNI et al.

NOBUKUNI et al.

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12/17/04